

STL100NH3LL

N-CHANNEL 30V - 0.0032Ω - 25A PowerFLATTM (6x5) STripFETTM III MOSFET

PRODUCT PREVIEW

Table 1: General Features

TYPE	V _{DSS}	R _{DS(on)}	I _D
STL100NH3LL	30 V	< 0.0035 Ω	25 A (1)

- TYPICAL $R_{DS}(on) = 0.0032\Omega$ @ 10V
- IMPROVED DIE-TO-FOOTPRINT RATIO
- VERY LOW PROFILE PACKAGE (1mm MAX)
- VERY LOW THERMAL RESISTANCE
- CONDUCTION LOSSES REDUCED
- SWITCHING LOSSES REDUCED

DESCRIPTION

The STL100NH3LL utilizes the latest advanced design rules of ST's proprietary STripFET™ Technology. This process complete to unique metallization technique realised the most advanced low voltage MOSFET in PowerFLAT(6x5). The Chipscaled PowerFLAT™ package allows a significant board space saving, still boosting the performance.

APPLICATIONS

- HIGH-EFFICIENCY DC-DC CONVERTERS
- SYNCHRONOUS RECTIFICATION

Figure 1: Package

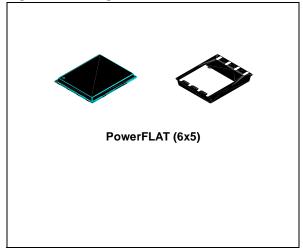


Figure 2: Internal Schematic Diagram

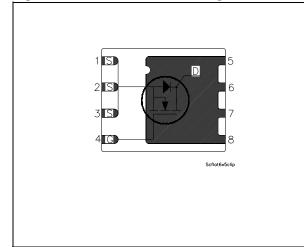


Table 2: Order Codes

SALES TYPE	MARKING	PACKAGE	PACKAGING
STL100NH3LL	L100NH3LL	PowerFLAT™(6x5)	TAPE & REEL

Rev. 4

October 2005 1/10

Table 3: Absolute Maximum ratings

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source Voltage (V _{GS} = 0)	30	V
V_{GS}	Gate- source Voltage	±16	V
I _D (2)	Drain Current (continuous) at T _C = 25°C	100	А
I _D	Drain Current (continuous) at T _C = 100°C	15.6	А
I _{DM} (3)	Drain Current (pulsed)	100	А
I _D (1)	Drain Current (continuous) at T _C = 25°C	25	А
P _{TOT} (2)	Total Dissipation at T _C = 25°C	80	W
P _{TOT} (1)	Total Dissipation at T _C = 25°C	4	W
	Derating Factor	0.03	W/°C
T _{stg} T _j	Storage Temperature Operating Junction Temperature Range	-55 to 150	°C

Table 4: Thermal Data

Rthj- _C	Thermal Resistance Junction-case (Drain) (Steady State)	1.56	°C/W
Rthj-pcb (4)	Thermal Operating Junction-pcb	31.3	°C/W

Table 5: Avalanche Characteristics

Symbol	Parameter	Max Value	Unit
I _{AV}	Not-Repetitive Avalanche Current (pulse width limited by T_j max)	12.5	Α
E _{AS}	Single Pulse Avalanche Energy (starting $T_j = 25$ °C, $I_D = I_{AV}$, $V_{DD} = 24$ V)	1.3	J

ELECTRICAL CHARACTERISTICS (T_{CASE} =25°C UNLESS OTHERWISE SPECIFIED)

Table 6: On/Off

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0$	30			V
I _{DSS}	Zero Gate Voltage Drain Current (V _{GS} = 0)	V_{DS} = Max Rating V_{DS} = Max Rating, T_{C} = 125 °C			1 10	μΑ μΑ
I _{GSS}	Gate-body Leakage Current (V _{DS} = 0)	V _{GS} = ± 16V			±100	nA
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1			V
R _{DS(on)}	Static Drain-source On Resistance	$V_{GS} = 10V$, $I_D = 12.5$ A $V_{GS} = 4.5V$, $I_D = 12.5$ A		0.0032 0.004	0.0035 0.005	Ω Ω

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ELECTRICAL CHARACTERISTICS (CONTINUED)

Table 7: Dynamic

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
g _{fs} (5)	Forward Transconductance	V _{DS} = 10 V _, I _D =12,5 A		30		S
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25V, f = 1 \text{ MHz}, V_{GS} = 0$		4450 655 50		pF pF pF
t _{d(on)} t _r t _{d(off)} t _r	Turn-on Delay Time Rise Time Turn-off Delay Time Fall Time	$V_{DD} = 15 \text{ V}, I_{D} = 12.5 \text{ A},$ $R_{G} = 4.7 \Omega V_{GS} = 10 \text{ V}$ (see Figure 15)		18 50 75 8		ns ns ns ns
Q _g Q _{gs} Q _{gd}	Total Gate Charge Gate-Source Charge Gate-Drain Charge	$V_{DD} = 15V, I_{D} = 25 \text{ A},$ $V_{GS} = 4.5V$ (see Figure 17)		30 12.5 10	40	nC nC nC
R _G	Gate Input Resistance	f=1 MHz Gate DC Bias = 0 Test Signal Level = 20mV Open Drain	1	2	3	Ω

Table 8: Source Drain Diode

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
I _{SD} I _{SDM} (3)	Source-drain Current Source-drain Current (pulsed)				25 100	A A
V _{SD} (4)	Forward On Voltage	I _{SD} = 25 A, V _{GS} = 0			1.3	V
t _{rr} Q _{rr} I _{RRM}	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	I_{SD} = 25 A, di/dt = 100A/ μ s V_{DD} = 25 V, T_j = 150°C (see test circuit, Figure 16)		32 34 2.1		ns nC A

Note:

- (1) The value is according $R_{thj\text{-pcb}}$

- (2)The value is according Rthj-cc (2)The value is according Rthj-c (3) Pulse width limited by safe operating area. (4) When mounted on FR-4 board of 1 in², 2oz Cu, t < 10 sec (5) Pulsed: Pulse duration = 300µs, duty cycle 1.5%

Figure 3: Safe Operating Area

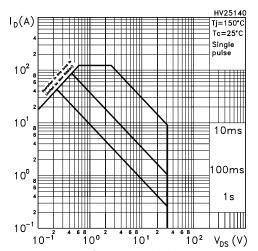


Figure 4: Output Characteristics

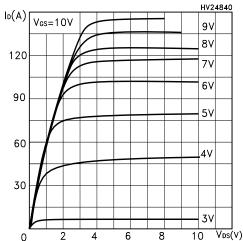


Figure 5: Transconductance

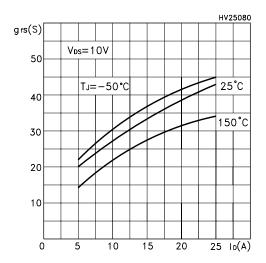


Figure 6: Thermal Impedance

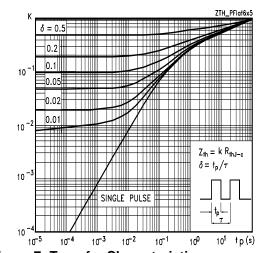


Figure 7: Transfer Characteristics

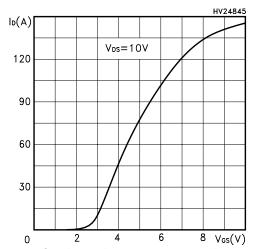
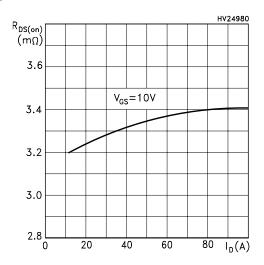


Figure 8: Static Drain-source On Resistance



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Figure 9: Gate Charge vs Gate-source Voltage

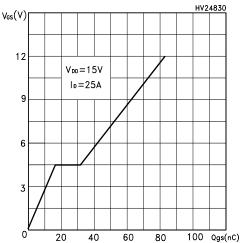


Figure 10: Normalized Gate Thereshold Voltage vs Temperature

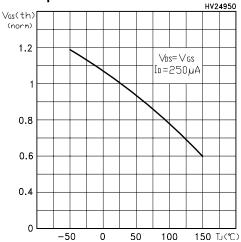


Figure 11: Normalized On Resistance vs Temperature

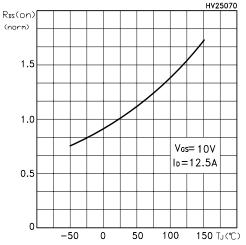


Figure 12: Capacitance Variations

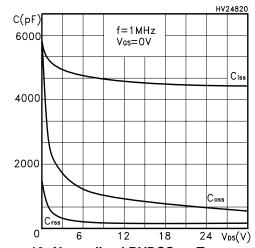


Figure 13: Normalized BVDSS vs Temperature

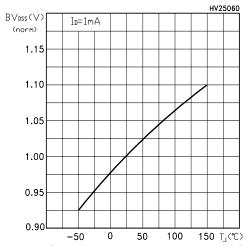


Figure 14: Source-Drain Diode Forward Characteristics

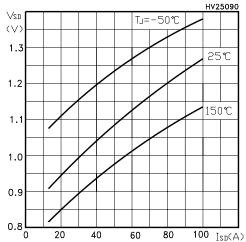


Figure 15: Switching Times Test Circuit For Resistive Load

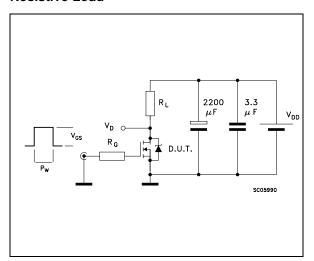


Figure 16: Test Circuit For Inductive Load Switching and Diode Recovery Times

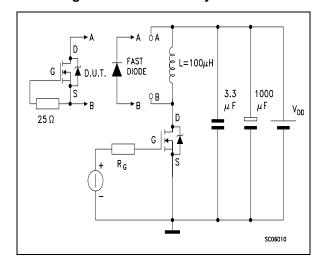
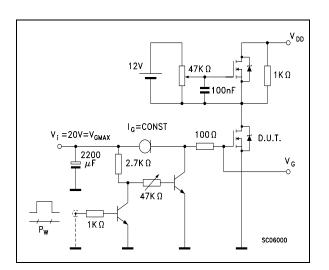


Figure 17: Gate Charge Test Circuit



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In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect . The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com

PowerFLAT™ (6x5) MECHANICAL DATA

DIM		mm.			inch	
DIM.	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
Α	0.80	0.83	0.93	0.031	0.032	0.036
A1		0.02	0.05		0.0007	0.0019
A3		0.20			0.007	
b	0.35	0.40	0.47	0.013	0.015	0.018
D		5.00			0.196	
D1		4.75			0.187	
D2	4.15	4.20	4.25	0.163	0.165	0.167
Е		6.00			0.236	
E1		5.75			0.226	
E2	3.43	3.48	3.53	0.135	0.137	0.139
E4	2.58	2.63	2.68		0.103	0.105
е		1.27			0.050	
L	0.70	0.80	0.90	0.027	0.031	0.035

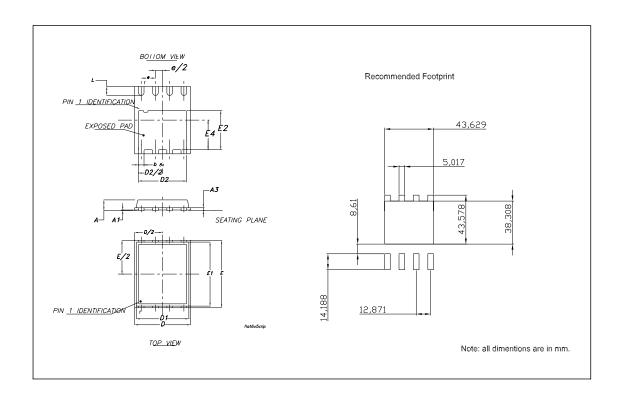


Table 9: Revision History

Date	Revision	Description of Changes
18-Apr-2005	1	First release
20-Jun-2005	2	Updated mechanical data
22-Jun-2005	3	New R _G value on table 6
10-Oct-2005	4	Inserted Ecopack indication

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